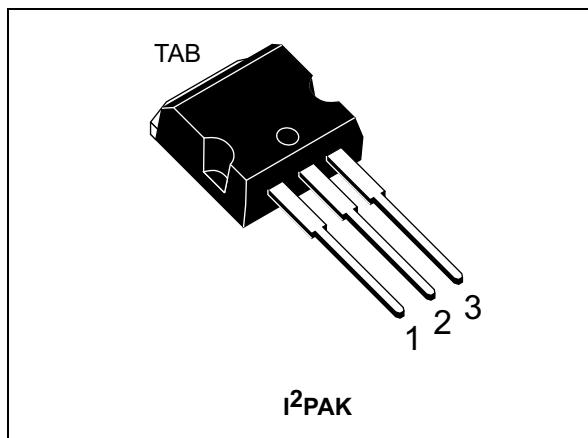


Automotive-grade N-channel clamped, 7 mΩ typ., 80 A fully protected Mesh overlay™ Power MOSFET in a I<sup>2</sup>PAK package

Datasheet - production data



**Figure 1. Internal schematic diagram**

## Features

Type	V <sub>DS</sub>	R <sub>DS(on) max.</sub>	I <sub>D</sub>
STB130NS04ZB-1	Clamped	9 mΩ	80 A

- Designed for automotive applications and AEC-Q101 qualified
- 100% avalanche tested
- Low capacitance and gate charge
- 175°C maximum junction temperature

## Applications

- High switching current
- Linear applications

## Description

This fully clamped MOSFET is produced using ST's latest advanced Mesh overlay process, which is based on an innovative strip layout. The inherent benefits of the new technology coupled with the extra clamping capabilities make this product particularly suitable for the harshest operation conditions, such as those encountered in the automotive environment. The device is also well-suited for other applications where extra ruggedness is required.

**Table 1. Device summary**

Order code	Marking	Package	Packaging
STB130NS04ZB-1	B130NS04ZB	I <sup>2</sup> PAK	Tube

## Contents

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# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source voltage	Clamped	V
$V_{GS}$	Gate-source voltage	Clamped	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	80	A
$I_D$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	60	A
$I_{DG}$	Drain gate current (continuous)	$\pm 50$	mA
$I_{GS}$	Gate source current (continuous)	$\pm 50$	mA
$I_{DM}^{(1)}$	Drain current (pulsed)	320	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	300	W
	Derating factor	2.0	W/ $^\circ\text{C}$
ESD	Gate-source human body model $C=100 \text{ pF}, R=1.5 \text{ k}\Omega$	4	kV
$T_J$ $T_{stg}$	Operating junction temperature Storage temperature	-55 to 175	$^\circ\text{C}$

1. Pulse width limited by safe operating area.

**Table 3. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case Max	0.50	$^\circ\text{C/W}$
$R_{thj-a}$	Thermal resistance junction-ambient Max	62.5	$^\circ\text{C/W}$

**Table 4. Avalanche characteristics**

Symbol	Parameter	Value	Unit
$I_{AS}$	Avalanche current, repetitive or not-repetitive (pulse width limited by $T_j$ Max)	80	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j=25^\circ\text{C}$ , $I_d=I_{ar}$ , $V_{dd}=30\text{V}$ )	500	mJ

## 2 Electrical characteristics

( $T_{CASE}=25^{\circ}\text{C}$  unless otherwise specified)

**Table 5. On/off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0$ $-40 < T_j < 175^{\circ}\text{C}$	33			V
$I_{DSS}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = 16 \text{ V}$ $V_{DS} = 16 \text{ V}, T_j = 125^{\circ}\text{C}$			10 100	$\mu\text{A}$ $\mu\text{A}$
$I_{GSS}$	Gate body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 10 \text{ V}$			10	nA
$V_{GSS}$	Gate-source breakdown voltage	$I_{GS} = \pm 100 \mu\text{A}$	18			V
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS} = I_D = 1 \text{ mA}$	2		4	V
$R_{DS(\text{on})}$	Static drain-source on resistance	$V_{GS} = 10 \text{ V}, I_D = 40 \text{ A}$		7	9	$\text{m}\Omega$

**Table 6. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$g_{fs}^{(1)}$	Forward transconductance	$V_{DS} = 15 \text{ V}, I_D = 40 \text{ A}$	-	50		S
$C_{iss}$	Input capacitance	$V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0$	-	2700		pF
$C_{oss}$	Output capacitance		-	1275		pF
$C_{rss}$	Reverse transfer capacitance		-	285		pF
$Q_g$	Total gate charge	$V_{DD} = 20 \text{ V}, I_D = 80 \text{ A}$ $V_{GS} = 10 \text{ V}$ (see Figure 15)	-	80	105	nC
$Q_{gs}$	Gate-source charge		-	20		nC
$Q_{gd}$	Gate-drain charge		-	27		nC

1. Pulsed: pulse duration=300 $\mu\text{s}$ , duty cycle 1.5%

**Table 7. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 17.5 \text{ V}, I_D = 40 \text{ A},$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 14)	-	40	-	ns
$t_r$	Rise time		-	10	-	ns
$t_{d(off)}$	Turn-off delay time		-	220	-	ns
$t_f$	Fall time		-	100	-	ns

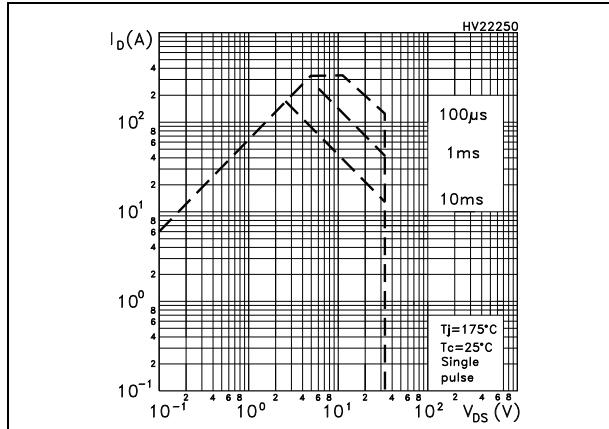
**Table 8. Source drain diode**

<b>Symbol</b>	<b>Parameter</b>	<b>Test conditions</b>	<b>Min.</b>	<b>Typ.</b>	<b>Max</b>	<b>Unit</b>
$I_{SD}$	Source-drain current		-		80	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		320	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD}=80A, V_{GS}=0$	-		1.5	V
$t_{rr}$	Reverse recovery time	$I_{SD}=80A,$ $di/dt = 100A/\mu s,$ $V_{DD}=25V, T_j=150^\circ C$ (see Figure 16)	-	90		ns
$Q_{rr}$	Reverse recovery charge		-	0.18		$\mu C$
$I_{RRM}$	Reverse recovery current		-	4		A

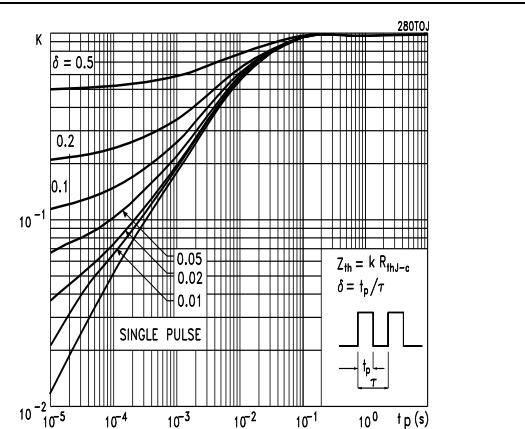
1. Pulse width limited by safe operating area
2. Pulsed: pulse duration=300 $\mu s$ , duty cycle 1.5%

## 2.1 Electrical characteristics (curves)

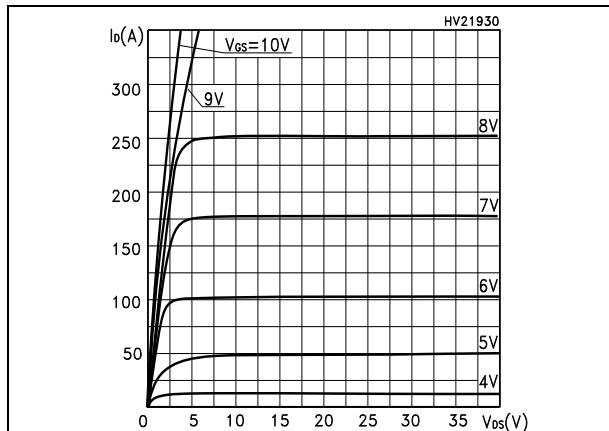
**Figure 2. Safe operating area**



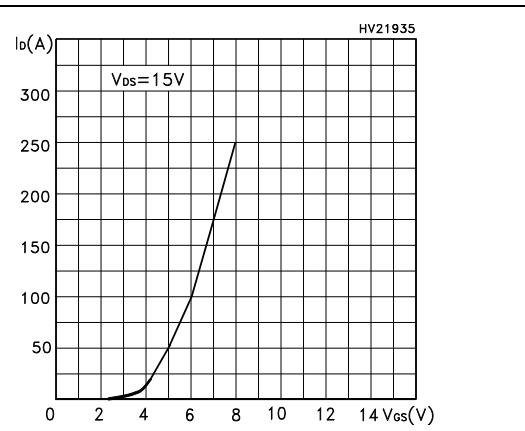
**Figure 3. Thermal impedance**



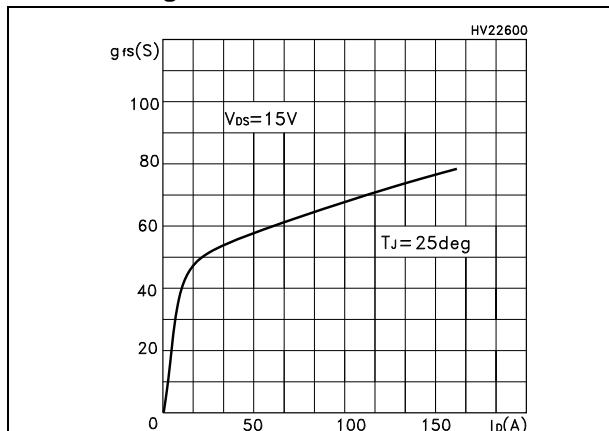
**Figure 4. Output characteristics**



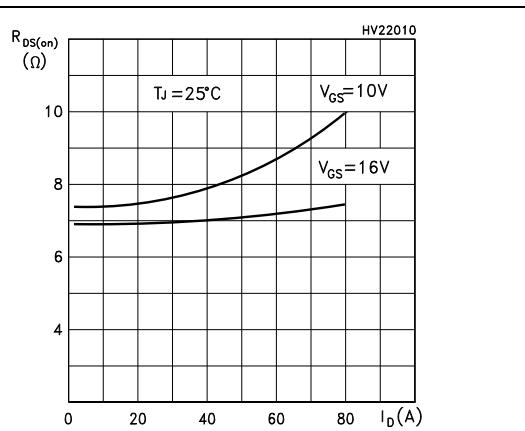
**Figure 5. Transfer characteristics**

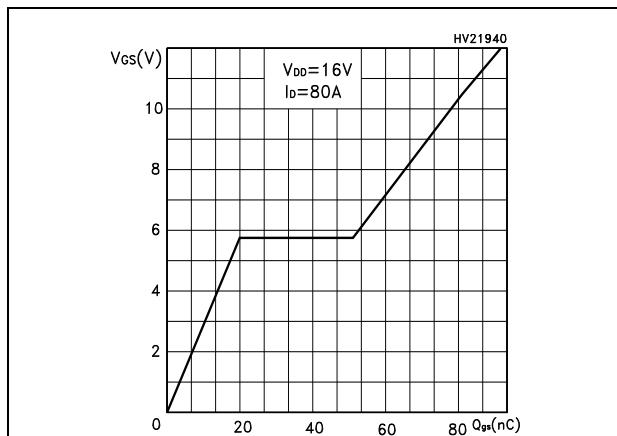
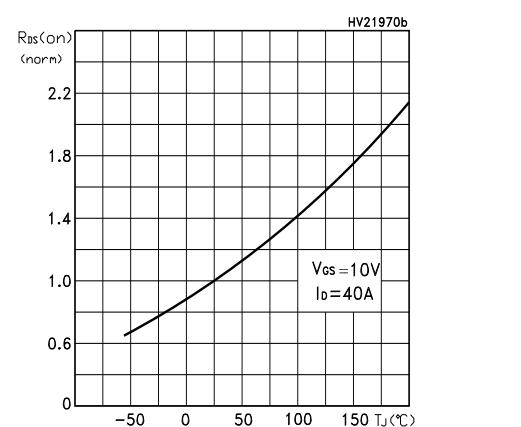
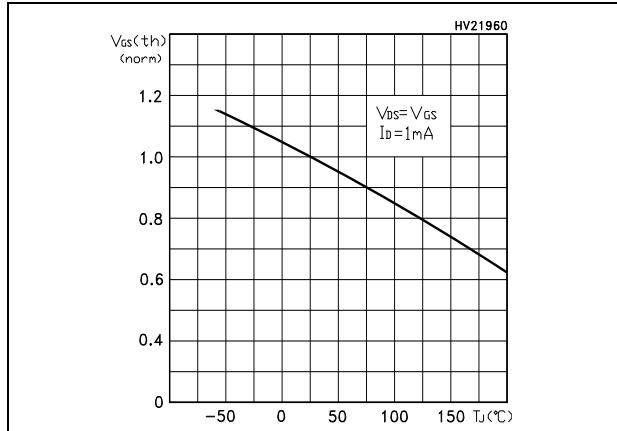
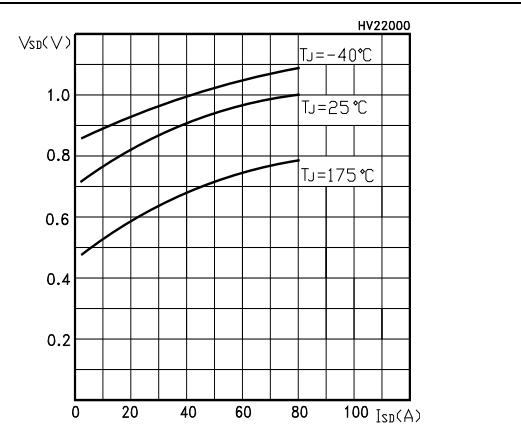
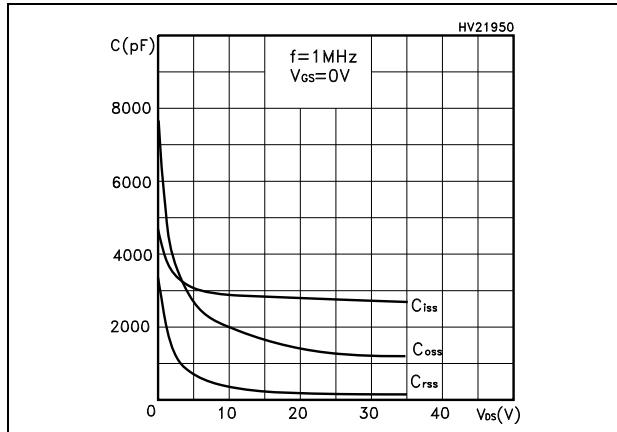
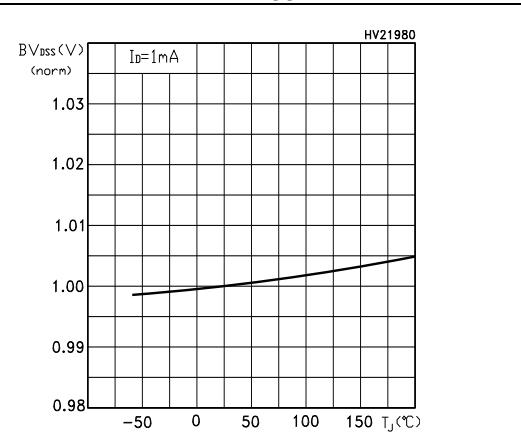


**Figure 6. Transconductance**



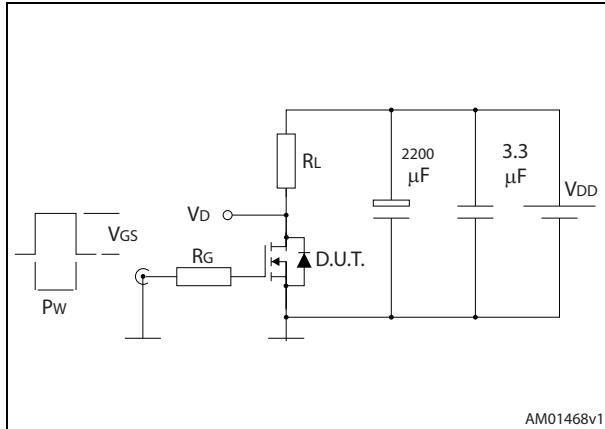
**Figure 7. Static drain-source on resistance**



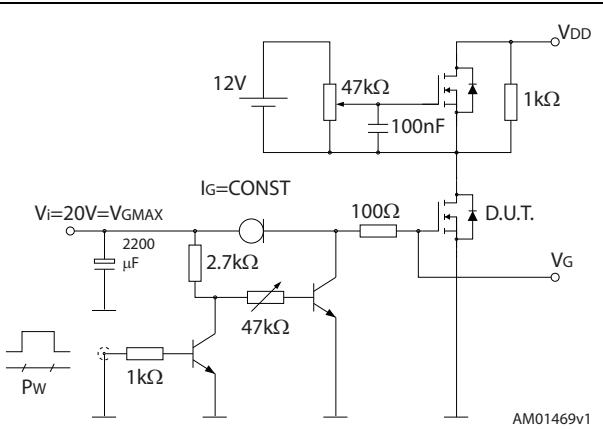
**Figure 8. Gate charge vs gate-source voltage****Figure 9. Normalized on resistance vs temperature****Figure 10. Normalized gate threshold voltage vs temperature****Figure 11. Source-drain diode forward characteristics****Figure 12. Capacitance variations****Figure 13. Normalized  $B_{VDSS}$  vs temperature**

### 3 Test circuit

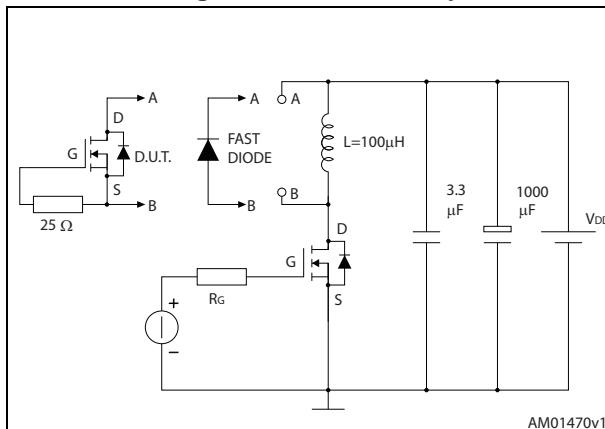
**Figure 14. Switching times test circuit for resistive load**



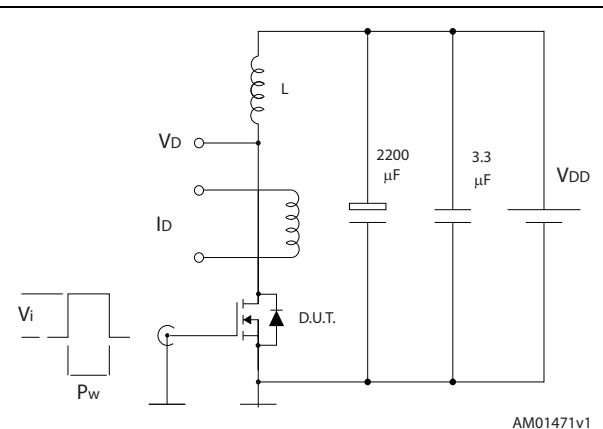
**Figure 15. Gate charge test circuit**



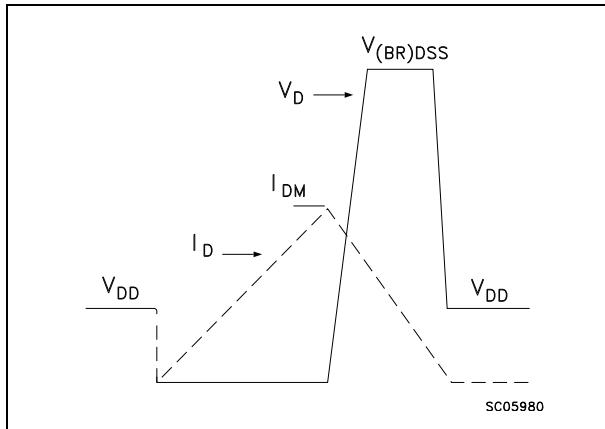
**Figure 16. Test circuit for inductive load switching and diode recovery times**



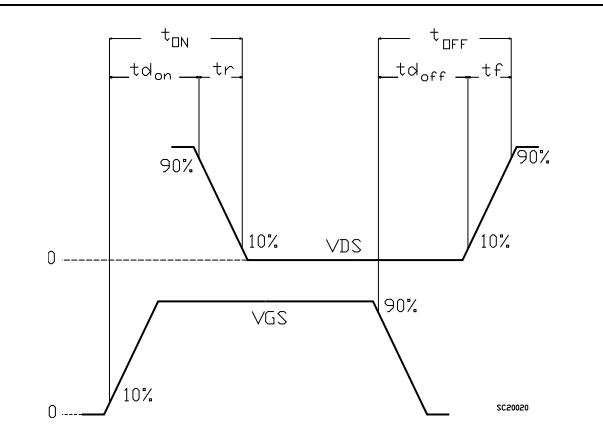
**Figure 17. Unclamped Inductive load test circuit**



**Figure 18. Unclamped inductive waveform**



**Figure 19. Switching time waveform**

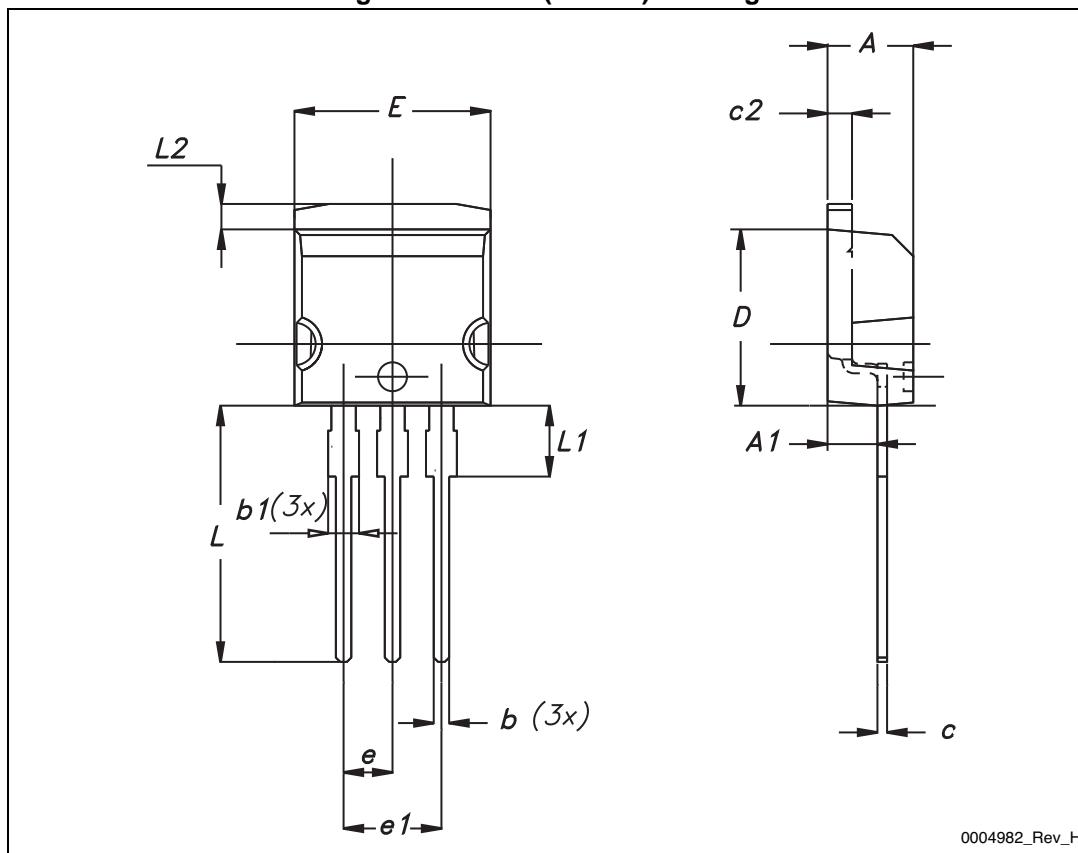


## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK® is an ST trademark.

Table 9. I<sup>2</sup>PAK (TO-262) mechanical data

DIM.	mm.		
	min.	typ	max.
A	4.40		4.60
A1	2.40		2.72
b	0.61		0.88
b1	1.14		1.70
c	0.49		0.70
c2	1.23		1.32
D	8.95		9.35
e	2.40		2.70
e1	4.95		5.15
E	10		10.40
L	13		14
L1	3.50		3.93
L2	1.27		1.40

Figure 20. I<sup>2</sup>PAK (TO-262) drawing

## 5 Revision history

**Table 10. Revision history**

Date	Revision	Changes
16-Sep-2014	1	First release.

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